





SLF65R280E7

650V N-Channel Multi-EPI Super-JMOSFET

General Description

This Power MOSFET is produced using Msemitek's Advanced Super-Junction technology.

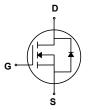
This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for AC/DC power conversion in switching mode operation for higher efficiency.

Features

- 15A, 650V, $R_{DS(on)typ}$ = 0.28 Ω @ V_{GS} = 10 V
- Low gate charge (typical 19.6nC)
- Lower Gate Resistance
- 100% Avalanche Tested
- Pb-free and RoHS Compliant





Absolute Maximum Ratings

T_C = 25°C unless otherwise noted

Symbol	Parameter		SLF65R280E7	Units
V_{DSS}	Drain-Source Voltage		650	V
	Drain Current - Continuous (T _C = 25°C)		15	А
I _D	- Continuous (T _C = 100°C)		8	А
I_{DM}	Drain Current - Pulsed	(Note 1)	45	А
V _{GSS}	Gate-Source Voltage		±30	V
EAS	Single Pulsed Avalanche Energy	(Note 2)	710	mJ
I _{AR}	Avalanche Current	(Note 1)	3.0	А
E _{AR}	Repetitive Avalanche Energy		1.11	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	20	V/ns
dv/dt	MOSFET dv/dt		100	
ם	Power Dissipation (T _C = 25°C)		30	W
P_D	- Derate above 25°C		0.24	W/°C
T_{J}, T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T∟	Maximum lead temperature for soldering purp 1/8" from case for 5 seconds	oses,	300	°C

^{*} Drain current limited by maximum junction temperature.

Thermal Characteristics

Symbol	Parameter	SLF65R280E7	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	4.1	°C/W
$R_{\theta JS}$	Thermal Resistance, Case-to-Sink Typ.		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking

Symbol

ĺ	Part Number	Top Marking	Package	Packing Method	MOQ	QTY
ĺ	SLF65R280E7	SLF65R280E7	TO-220F	Tube	1000	5000

Electrical Characteristics

Parameter

T_C = 25°C unless otherwise noted

Test Conditions

Min

Тур

Max

Units

Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250mA	650			V
DVDSS	Brain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 0.25 \text{uA}, T_{J} = 150^{\circ}\text{C}$	650		-	V
1	Zero Gate Voltage Drain Current	V _{DS} = 600 V, V _{GS} = 0 V		-	1	uA
IDSS	l _{DSS} Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$		2	-	uA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 30 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -30 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250uA$	2.5		4.5	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 7.5 A	1	238	280	mΩ
Rg	Gate resistance	F=1MHZ		1.1		Ω

Dynamic Characteristics

	Ciss	Input Capacitance	$V_{DS} = 400 \text{ V}, V_{GS} = 0 \text{V},$	1	780	-	pF
	C_{oss}	Output Capacitance	f = 1MHz	1	23	-	pF
	$C_{o(tr)}$	Time Related Output Capacitance	V _{DS} = 0V to 400 V. V _{GS} = 0 V		300		pF
Ī	C _{o(er)}	Energy Related Output Capacitance	V _{DS} – UV to 400 V, V _{GS} – U V		37		pF

Switching Characteristics

$t_{\sf d(on)}$	Turn-On Delay Time	$V_{DS} = 400 \text{ V}, I_{D} = 5.3 \text{A}$		7.6		ns
t _r	Turn-On Rise Time	V_{GS} = 10 V, R_{G} = 10 Ω See Figure 13	-	6.7	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	38.2	-	ns
t _f	Turn-Off Fall Time		-	8.4	-	ns
Q_g	Total Gate Charge	\/ -400\/ L - 5 2A		19.6		nC
Qgs	Gate-Source Charge	$V_{DS} = 400 \text{ V}, I_{D} = 5.3\text{A},$ $V_{GS} = 10 \text{ V}$	-	3.7	-	nC
Q_{gd}	Gate-Drain Charge	VGS = 10 V		9.7		nC

Drain-Source Diode Characteristics and Maximum Ratings

	Is	Maximum Continuous Drain-Source Diode Forward Current				15	Α
	I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current		1	-	45	Α
ſ	V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 5.3 \text{A}$		-	1.2	V
I	t _{rr}	Reverse Recovery Time	$V_{DD} = 400 \text{ V}, I_S = 5.3\text{A},$	-	234		ns
ſ	Qrr	Reverse Recovery Charge	dl _F / dt = 100 A/us		2.2		uC

XNotes:

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2. L=79mH, I_{AS} = 3 A, R_{G} = 25 Ω , starting T_{J} = 25°C. 3. $I_{SD} \le 5.3$ A, di/dt ≤ 100 A/ μ s, $V_{DD} \le 400$ V, starting T_{J} = 25°C.

Typical Characteristics

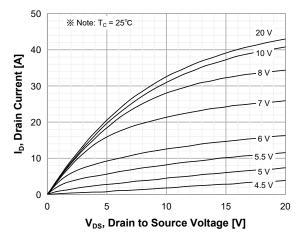
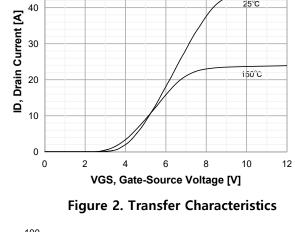


Figure 1. On-Region Characteristics



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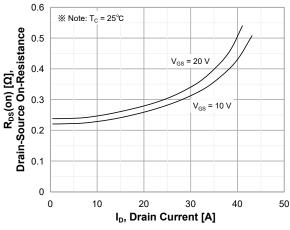


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

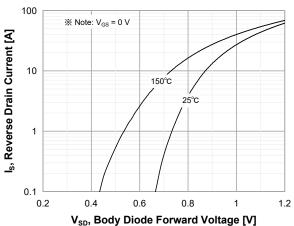


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

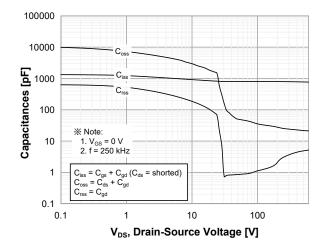


Figure 5. Capacitance Characteristics

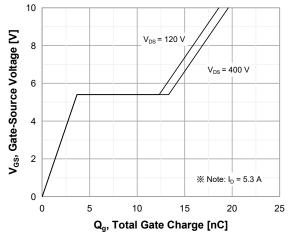
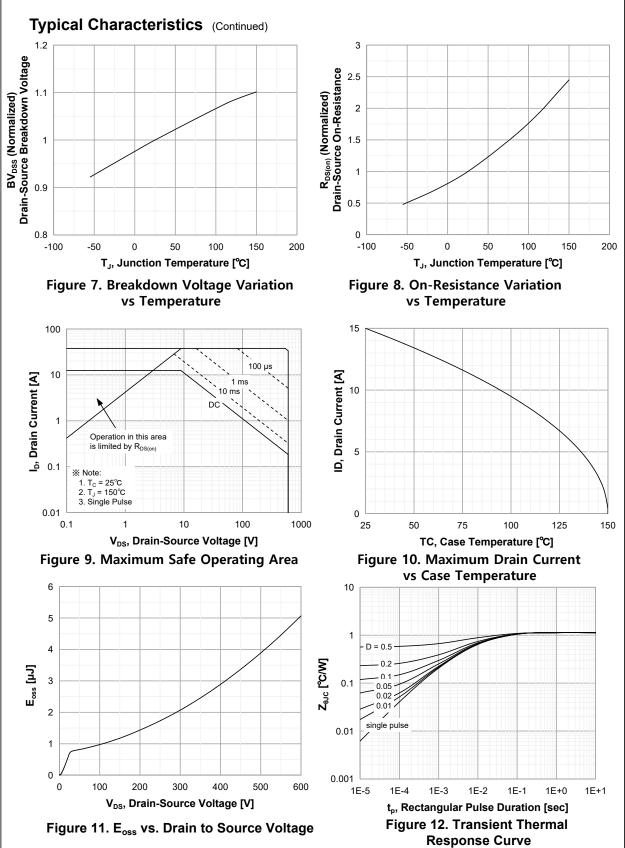
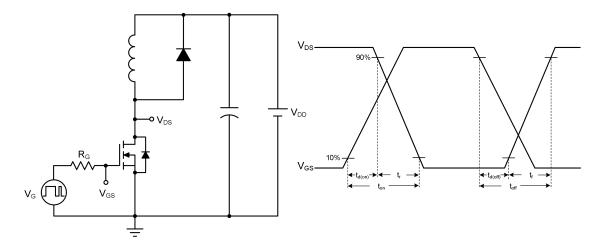


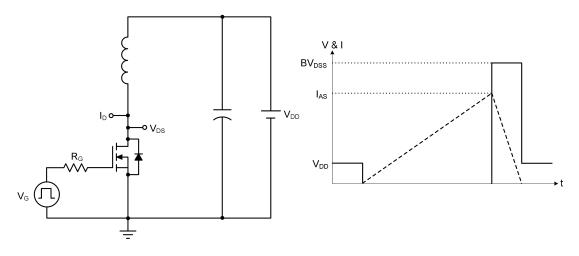
Figure 6. Gate Charge Characteristics



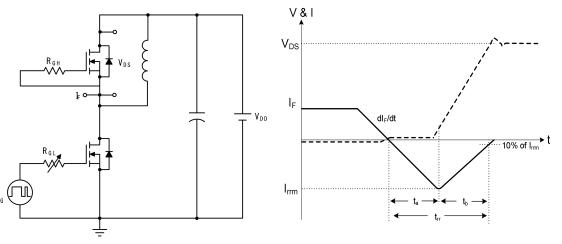
Inductive Load Switching Test Circuit and Waveforms



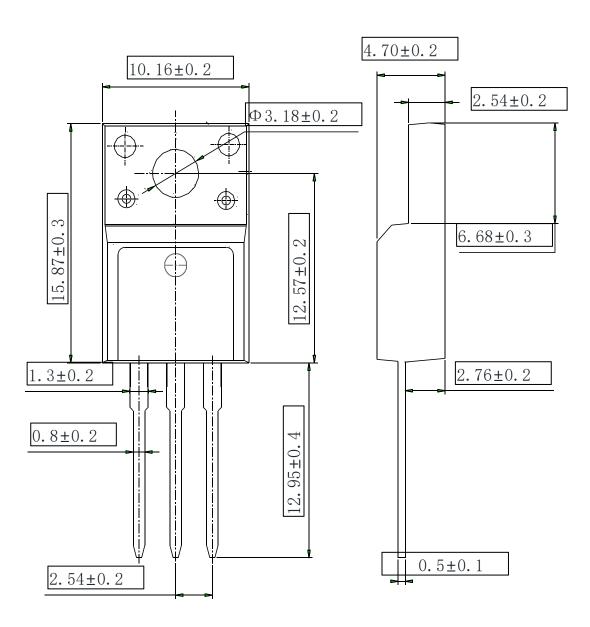
Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit and Waveforms



TO-220F OUTLINE



NOTE:

1The plastic package is not marked as smooth surfaceRa=0.1; Subglossy surfaceRa=0.8 2. Undeclared tolerance \pm 0.15, Unmarked filletRmax=0.25

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